PH3330L

N-channel TrenchMOS logic level FET

Rev. 02 — 22 October 2008

Product data sheet

1. Product profile

1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

1.3 Applications

- DC-to-DC converters
- Notebook computers

- Switched-mode power supplies
- Voltage regulators

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 150 °C	-	-	30	V
I _D	drain current	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	100	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	62.5	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 12 \text{ V}; \text{ see } \frac{\text{Figure 12}}{\text{Figure 13}};$	-	6.9	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 10}}{\text{1}};$ $\text{see } \frac{\text{Figure 11}}{\text{1}}$	-	2.3	3.3	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		_
2	S	source	mb	D
3	S	source		$G \longrightarrow \overline{A}$
4	G	gate	Qj	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 S
			SOT669 (LFPAK)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PH3330L	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}$	-	30	V
V_{DGR}	drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 150 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
V_{GS}	gate-source voltage		-20	20	V
I_D	drain current	$V_{GS} = 10 \text{ V}$; $T_{mb} = 25 \text{ °C}$; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	100	Α
		V _{GS} = 10 V; T _{mb} = 100 °C; see <u>Figure 1</u>	-	54.2	Α
I _{DM}	peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	300	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	62.5	W
T _{stg}	storage temperature		-55	150	°C
Tj	junction temperature		-55	150	°C
Source-dra	ain diode				
Is	source current	$T_{mb} = 25 ^{\circ}C$	-	52	Α
I _{SM}	peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	208	Α
Avalanche	ruggedness				
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 70 A; V_{sup} ≤ 30 V; t_p = 0.15 ms; R_{GS} = 50 Ω; unclamped	-	245	mJ

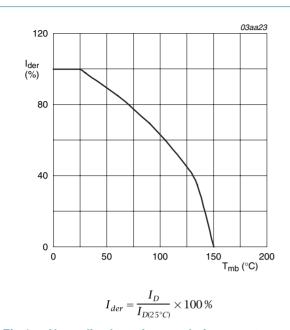


Fig 1. Normalized continuous drain current as a function of mounting base temperature

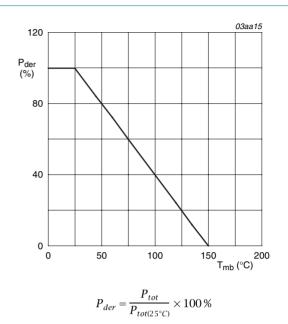
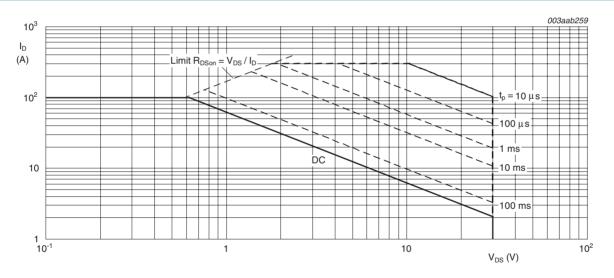


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25 \,^{\circ}C; I_{DM}$ is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

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Thermal characteristics 5.

Thermal characteristics Table 5.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	2	K/W

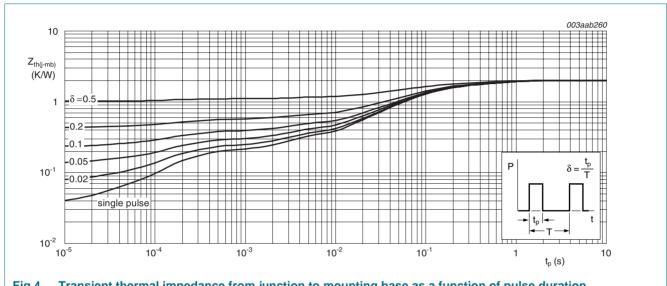


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

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6. Characteristics

Table 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see Figure 8; see Figure 9	1.3	1.7	2.15	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 150 \text{ °C}$; see <u>Figure 8</u> ; see <u>Figure 9</u>	8.0	-	-	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see Figure 8; see Figure 9	-	-	2.6	V
I _{DSS}	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	100	μΑ
I _{GSS}	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
R _{DSon}	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 25 °C; see Figure 10; see Figure 11	-	2.3	3.3	mΩ
		V_{GS} = 10 V; I_D = 25 A; T_j = 150 °C; see Figure 11; see Figure 10	-	4.1	6	mΩ
		$V_{GS} = 4.5 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see Figure 10; see Figure 11	-	3.4	4.5	mΩ
R _G	gate resistance	f = 1 MHz	-	0.7	-	Ω
Dynamic	characteristics					
$Q_{G(tot)}$	total gate charge	I_D = 25 A; V_{DS} = 12 V; V_{GS} = 4.5 V; see Figure 12; see Figure 13	-	30.5	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 4.5 \text{ V}$	-	28.5	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}$; $V_{DS} = 12 \text{ V}$; $V_{GS} = 4.5 \text{ V}$; see	-	15.4	-	nC
Q _{GS1}	pre-threshold gate-source charge	Figure 12; see Figure 13	-	7.7	-	nC
Q _{GS2}	post-threshold gate-source charge		-	7.7	-	nC
Q_{GD}	gate-drain charge		-	6.9	-	nC
V _{GS(pl)}	gate-source plateau voltage	I_D = 25 A; V_{DS} = 12 V; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	3.4	-	V
C _{iss}	input capacitance	$V_{DS} = 12 \text{ V; } V_{GS} = 0 \text{ V; } f = 1 \text{ MHz;}$ $T_j = 25 \text{ °C; see } \frac{\text{Figure } 14}{\text{Figure } 14}$	-	4840	-	pF
		$V_{DS} = 0 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25 \text{ °C}$	-	5380	-	pF
C _{oss}	output capacitance	V _{DS} = 12 V; V _{GS} = 0 V; f = 1 MHz;	-	960	-	pF
C _{rss}	reverse transfer capacitance	T _j = 25 °C; see <u>Figure 14</u>	-	410	-	pF

 Table 6.
 Characteristics ...continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
t _{d(on)}	turn-on delay time	V_{DS} = 12 V; R_L = 0.5 Ω ; V_{GS} = 4.5 V;	-	41	-	ns
t _r	rise time	$R_{G(ext)} = 5.6 \Omega$	-	75	-	ns
t _{d(off)}	turn-off delay time		-	52	-	ns
t _f	fall time		-	27	-	ns
Source-di	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see Figure 15	-	0.82	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/s}$; $V_{GS} = 0 \text{ V}$; $V_{DS} = 25 \text{ V}$	-	52	-	ns
Q _r	recovered charge		-	23	-	nC

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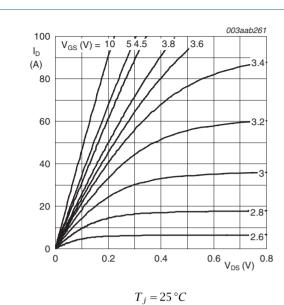
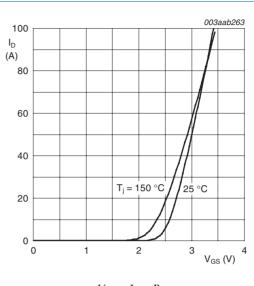


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values



 $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

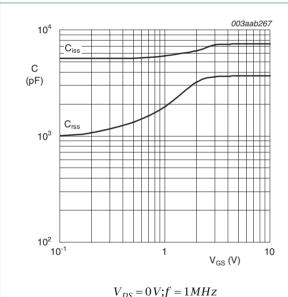
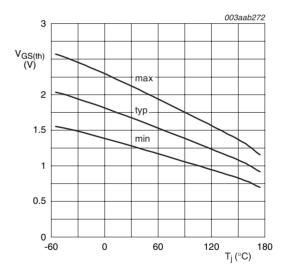


Fig 7. Input and reverse transfer capacitances as a function of gate-source voltage; typical values



$$I_D = 1 \, mA; V_{DS} = V_{GS}$$

Fig 8. Gate-source threshold voltage as a function of junction temperature

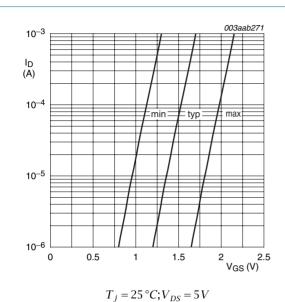


Fig 9. Sub-threshold drain current as a function of gate-source voltage

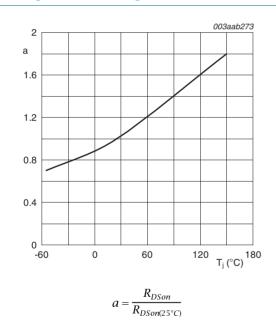


Fig 11. Normalized drain-source on-state resistance factor as a function of junction temperature

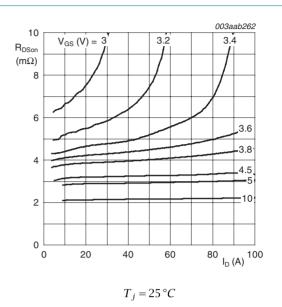


Fig 10. Drain-source on-state resistance as a function of drain current; typical values

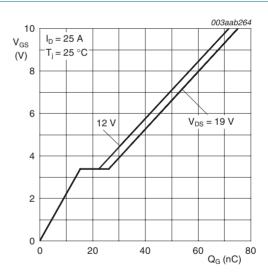


Fig 12. Gate-source voltage as a function of gate charge; typical values

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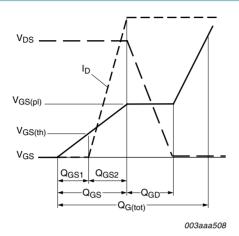
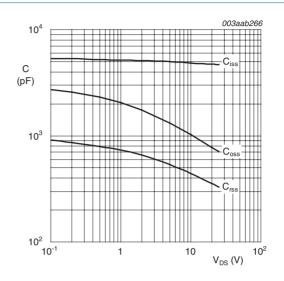
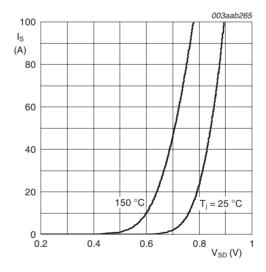


Fig 13. Gate charge waveform definitions



 $V_{GS} = 0V; f = 1MHz$

Fig 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $V_{GS} = 0V$

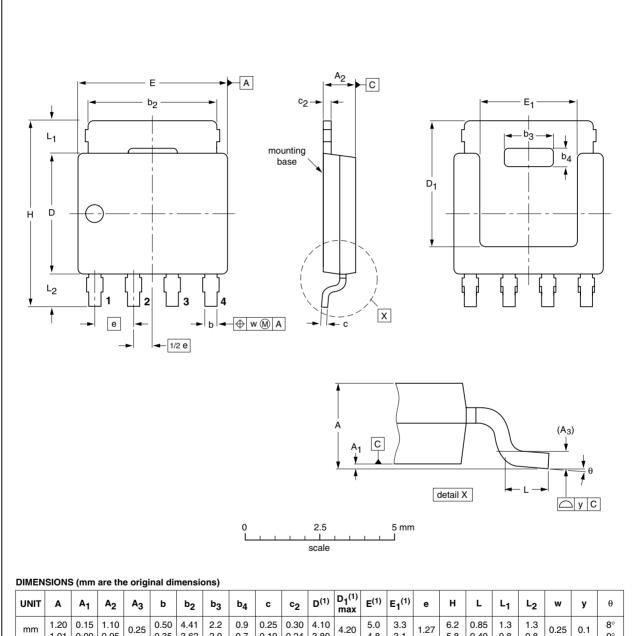
Fig 15. Source current as a function of source-drain voltage; typical values

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Package outline

Plastic single-ended surface-mounted package (LFPAK); 4 leads

SOT669



	UNIT	Α	A ₁	A ₂	A ₃	b	b ₂	b ₃	b ₄	С	c ₂	D ⁽¹⁾	D ₁ ⁽¹⁾ max	E ⁽¹⁾	E ₁ ⁽¹⁾	е	Н	L	L ₁	L ₂	w	у	θ
	mm	1.20 1.01	0.15 0.00	1.10 0.95	0.25	0.50 0.35	4.41 3.62	2.2 2.0	0.9 0.7	0.25 0.19	l .	4.10 3.80	4.20	5.0 4.8	3.3 3.1	1.27	6.2 5.8	0.85 0.40	1.3 0.8	1.3 0.8	0.25	0.1	8°
L		1.01	0.00	0.33		0.00	3.02	2.0	0.7	0.13	0.24	5.00		4.0	0.1		5.0	0.40	0.0	0.0			U

Note

1. Plastic or metal protrusions of 0.15 mm maximum per side are not included.

	OUTLINE		REFER	EUROPEAN	ISSUE DATE		
	VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
	SOT669		MO-235				04-10-13 06-03-16
					•		

Fig 16. Package outline SOT669 (LFPAK)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes					
PH3330L_2	20081022	Product data sheet	-	PH3330L_1					
Modifications:	difications: • The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.								
 Legal texts have been adapted to the new company name where appropriate. 									
PH3330L_1	20060201	Product data sheet	-	-					

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9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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11. Contents

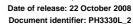
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